## Notice of References Cited Application/Control No. 10/584,865 Examiner ZEWDU BEYEN Applicant(s)/Patent Under Reexamination ANDERSSON, ANDERS Art Unit Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0010772 A1	01-2002	Kusano, Toshihiko	709/223
*	В	US-2002/0019853 A1	02-2002	Vange et al.	709/207
*	C	US-2002/0126656 A1	09-2002	Park, Do-Jun	370/352
*	D	US-6,469,993 B1	10-2002	Seo et al.	370/329
*	Е	US-6,519,640 B2	02-2003	Hattori et al.	709/224
*	F	US-2003/0195966 A1	10-2003	Fujii, Kenichi	709/228
*	G	US-2003/0186724 A1	10-2003	Tsutsumi et al.	455/561
*	Ι	US-2004/0098507 A1	05-2004	Thubert et al.	709/245
*	I	US-2005/0094675 A1	05-2005	Bhushan et al.	370/527
*	J	US-6,907,258 B2	06-2005	Tsutsumi et al.	455/512
*	K	US-7,257,404 B1	08-2007	Chow et al.	455/436
*	L	US-6,907,258	06-2005	Tsutsumi et al.	455/512
*	М	US-6,529,907	03-2003	Terakura et al.	707/9

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Р					
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	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.